

Powder Diffraction

**Volume 3
Number 3
1988**

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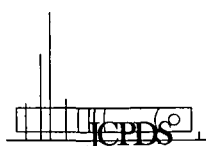
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Powder Diffraction

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Powder Diffraction

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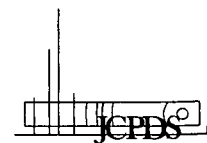
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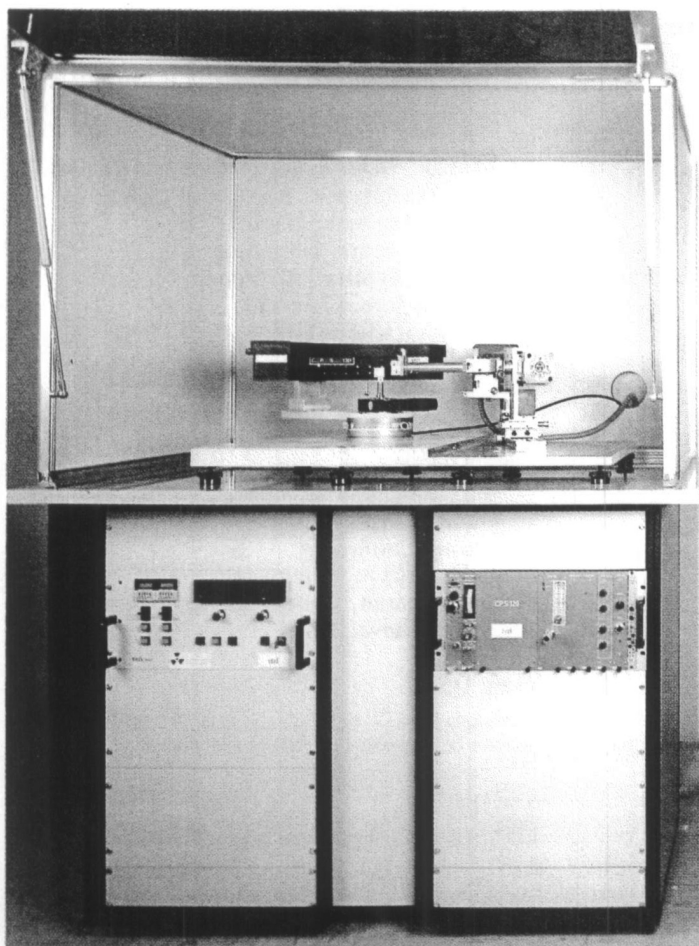
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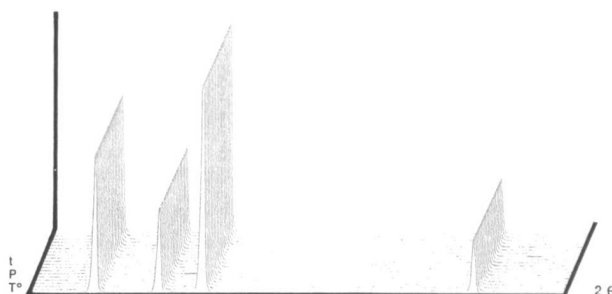
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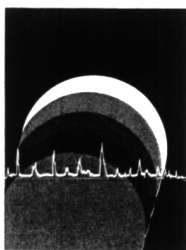
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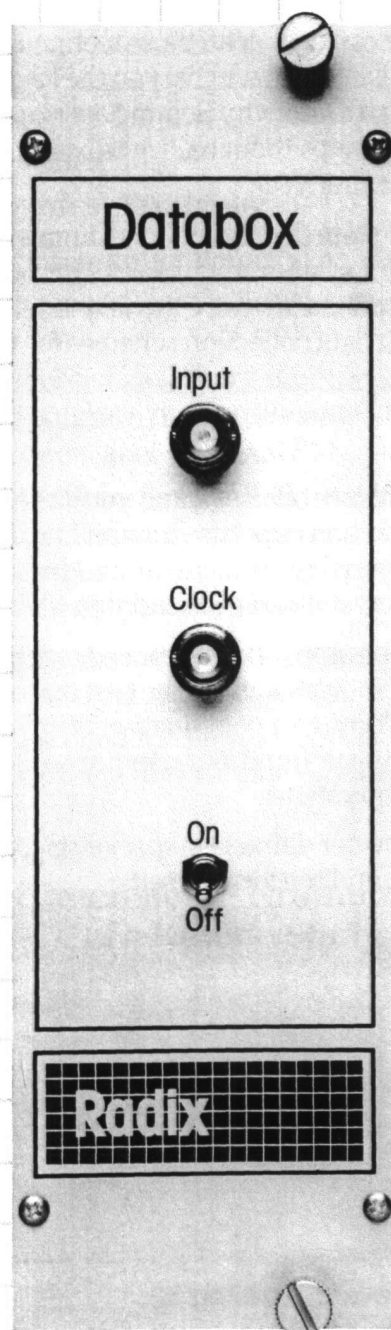
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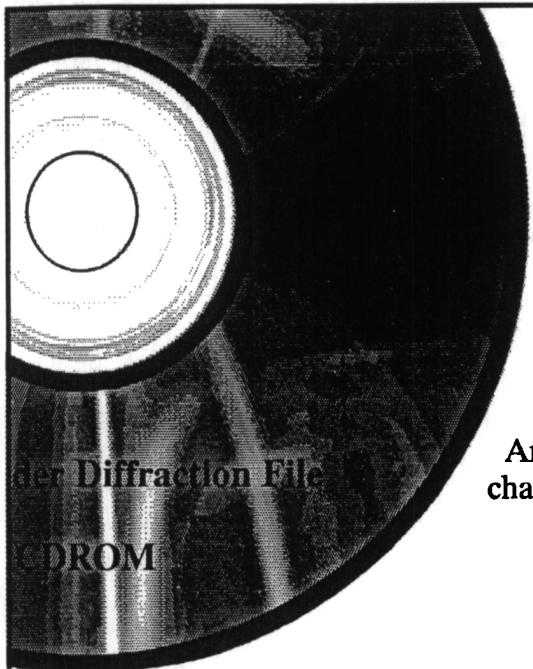
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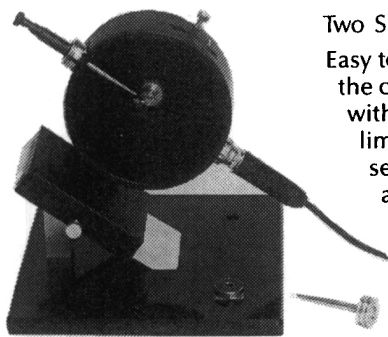


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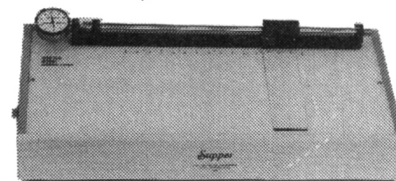
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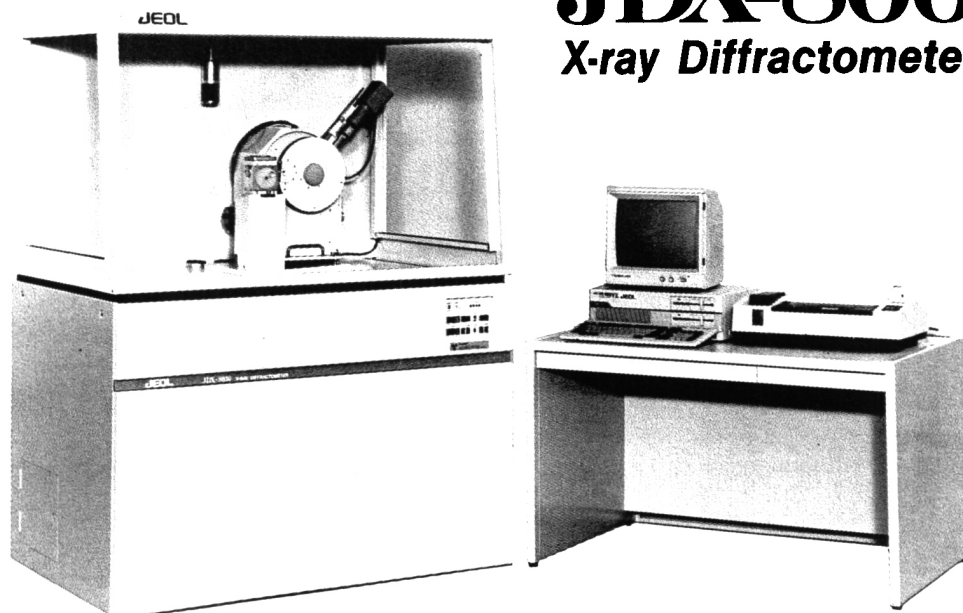
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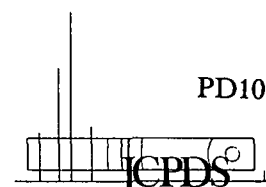
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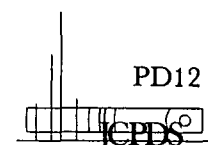
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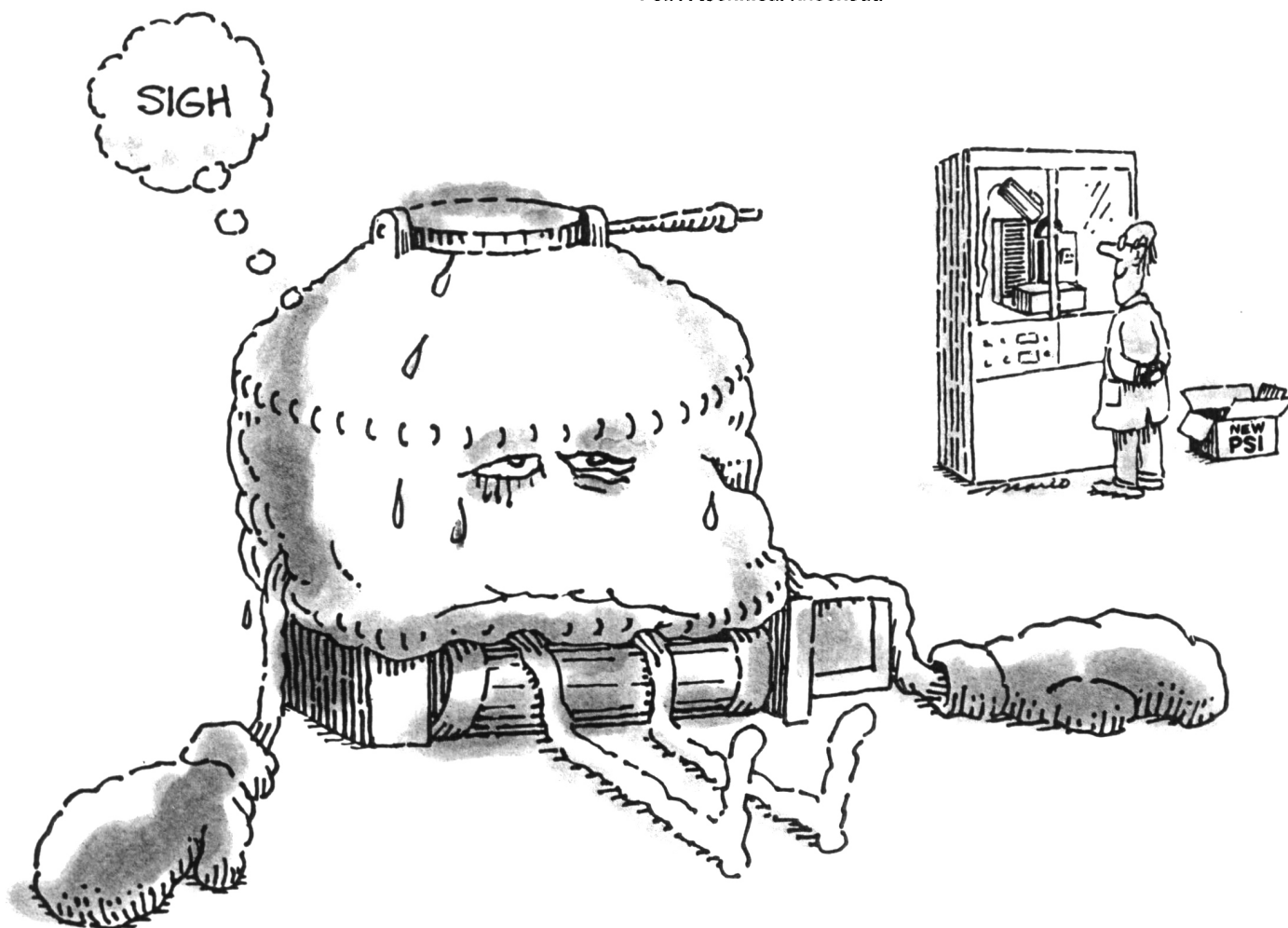
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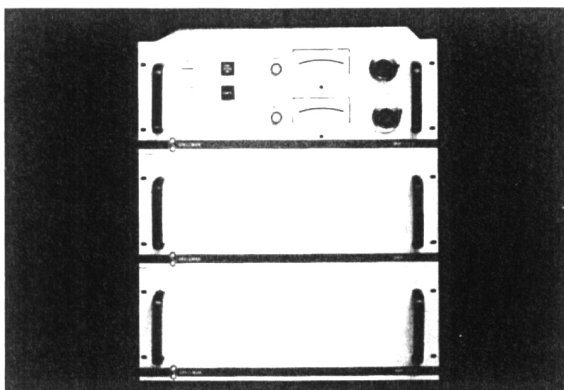
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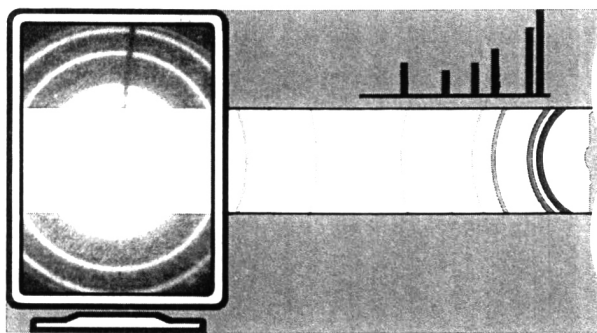
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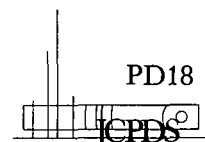
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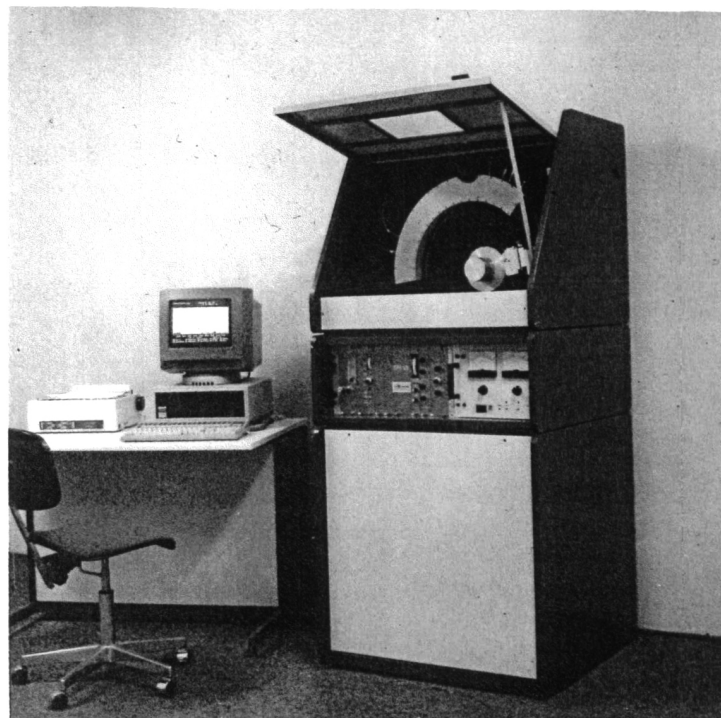
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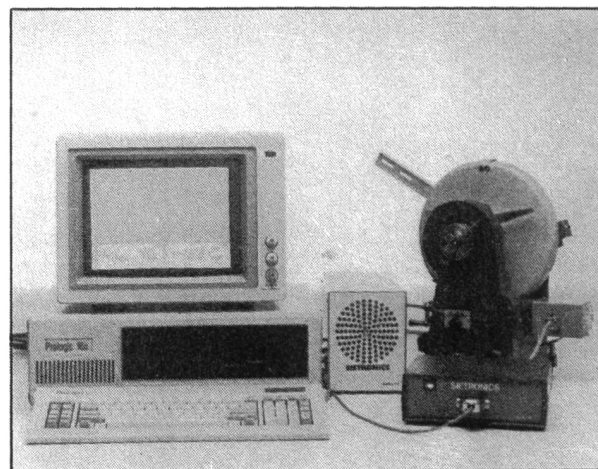
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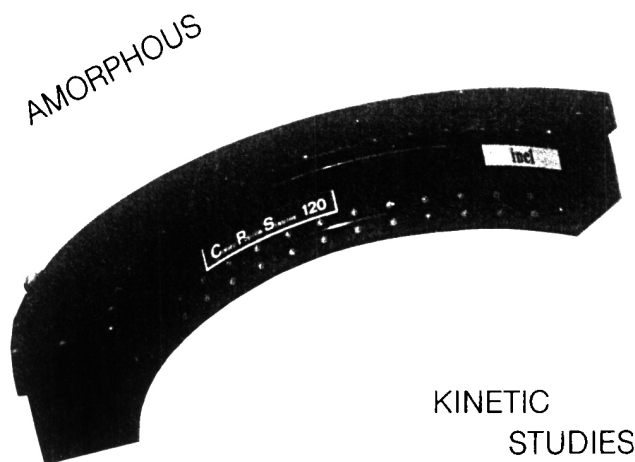
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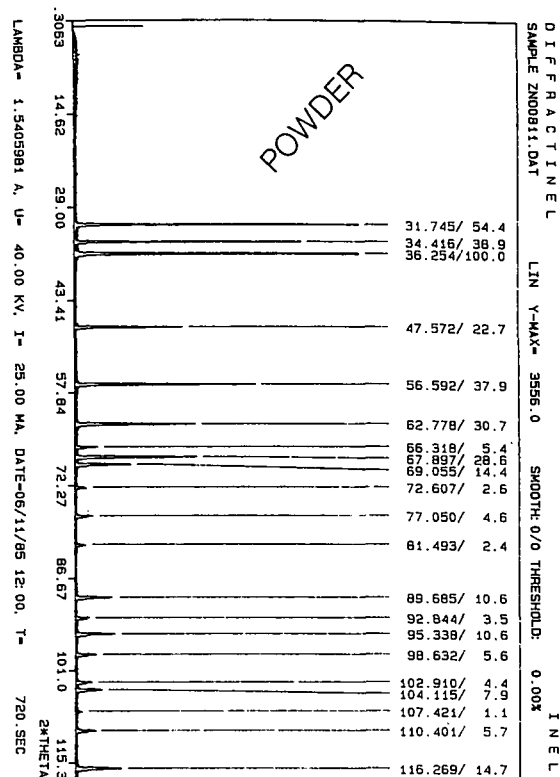
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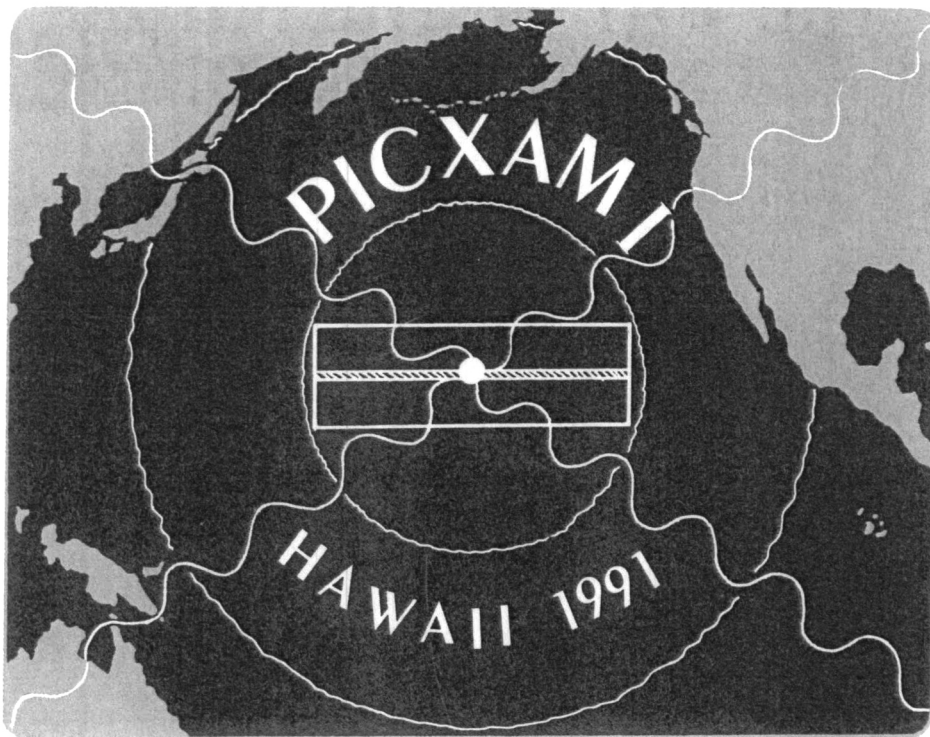
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Preliminary Announcement...

The first international conference on X-ray Analytical Methods for Materials Analysis will be held in Honolulu, August 15–19, 1991, at the Hilton Hawaiian Village.

Conference Theme...

To provide an international forum for discussion of X-ray methods based on Powder Diffraction, Fluorescence, Surface Analysis, Absorptiometry, Column Electron Diffraction and X-ray Emission.

Two, 2-day, post conference meetings will also be held on August 19 and 20, for XRD and XRF. Local venues to be announced.

PIXCAM is organized by:

The Australian X-ray Analytical Association
The Denver X-ray Conference
X-ray Chemical Analysis Group/
Japan Society for Analytical Chemistry

PIXCAM is cosponsored by:

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Pacific-International Congress on X-Ray Analytical Methods

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Editorial

Changes in the Staff of *Powder Diffraction*

We are pleased to announce two new appointments to the editorial staff of *Powder Diffraction*. Helein D. Hitchcock is the new Departments Editor, replacing Ron Anderson who has recently resigned that post, and Brian H. O'Connor will be the Regional Editor for Australia and New Zealand.

This issue is the first without the services of Ron Anderson as Departments Editor who was one of the members of the committee which formed *Powder Diffraction* in 1984. He developed and coordinated the Departments section. The usefulness of the information is recognized by all who read the Calendar of Meetings and the Meeting Reports, the activity reports of the International Centre for Diffraction Data, the announcements of Short Courses and Workshops, Book Reviews, Computer Comments, New Products and General Announcements. Ron's efforts will be sadly missed by the rest of us on the staff who know the role he has played throughout these formative years of *Powder Diffraction*.

Anderson brought to the organizing committee considerable experience in the operation of a technical publication because he had been the editor of The EMSA Bulletin of the Electron Microscope Society of America for several years. This experience was invaluable in the initial planning of the designs and layouts for *Powder Diffraction*. He also was instrumental in establishing the advertising structure of the Journal. This advertising provides a forum for the manufacturers to inform users of their products which is especially valuable considering the specialized readership. This advertising also helps offset the costs of publishing which contributes to the low subscription rates for *Powder Diffraction*.

I would like to thank Ron Anderson for these valuable years of service to *Powder Diffraction*. Without his contributions, the formation and operation of this Journal would have been considerably more difficult.

Further to the present announcement of staff changes, we also remind you that about one year ago Hans de Vries joined the editorial staff as the Regional Editor for Europe. His address is listed on the title page, and manuscripts originating in Europe should be sent to his office. Brian H. O'Connor, the Regional Editor for Australia and New Zealand, is located at Curtin University, Dept. of Applied Physics GPO Box U 1987, Perth 6001, Western Australia, Australia. Downunder manuscripts should be sent through this office. Helein D. Hitchcock, the new Departments Editor, can be reached at NASA, DM-MSL-1, Kennedy Space Center, FL 32899. All material for the Departments should be directed to her office. I welcome these new staff members and look forward to working with them for the future of *Powder Diffraction*.

Deane K. Smith
Editor-in-Chief